



# Bruker Dektak XT

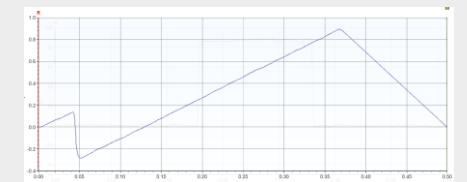
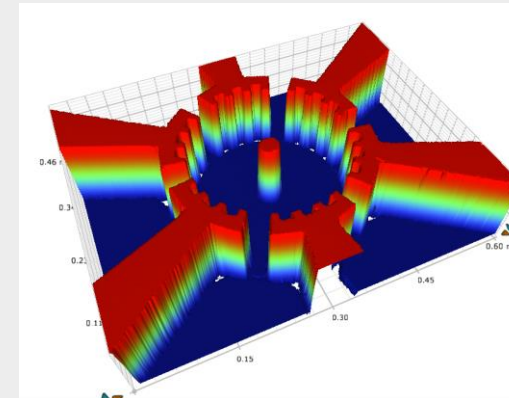


## Description

The Bruker Dektak XT is a contact profilometer, utilizes a fine diamond-tip stylus that contacts the sample while surface topography profiling as the sample stage moves. The Dektak XT enables the measurement of step heights and lateral dimensions, as well as surface roughness, thin film stress analysis, and providing 3D mapping capabilities.

## Specifications/Capabilities

- Vertical Resolution ( $1 \text{ \AA}$ ).
- Stylus: Diamond tip,  $2 \mu\text{m}$  radius .
- 3-D topological imaging.
- Motorized X-Y-theta stage.
- Stylus Tracking Force: 1 mg – 15 mg.
- Sample size : up to 8" (200mm) diameter .
- Repeatability : $4 \text{ \AA}$ .



## Link

<https://www.bruker.com/en/products-and-solutions/test-and-measurement/stylus-profilometers/dektakxt.html>